

Search Notes

Application/Control No.

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Examiner

M. Lee

Applicant(s)/Patent under
Reexamination

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Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	725, 726, 731-733, 553-558	11/23/2006	ML
375	316		
725	151		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference search history printout		11/23/2006	ML

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/23/2006	ML